

**Search Notes**

Application/Control No.

10/705,591

Examiner

Jason M. Han

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2875

**SEARCHED**

Class	Subclass	Date	Examiner
362	624	1/30/2006	JMH
362	627	1/30/2006	JMH
349	61-62	1/30/2006	JMH
349	65	1/30/2006	JMH
349	70	1/30/2006	JMH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	1/30/2006	JMH

**INTERFERENCE SEARCHED**

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